

Notice of Allowability	Application No.	Applicant(s)
	10/707,139	LAI, HAN-CHUNG
	Examiner	Art Unit
	Theresa T. Doan	2814
The MAILING DATE of this communication appears on the cover sheet with the correspondence address All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS. This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308. 1. This communication is responsive to 11/30/04.		
2. The allowed claim(s) is/are <u>9-23.</u>		
3. The drawings filed on 24 November 2003 are accepted by the Examiner.		
 4.		
Attachment(s) 1. ☑ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date 4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	6. Interview Summar Paper No./Mail Da 98), 7. Examiner's Amend	ate

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EXAMINER'S AMENDMENT

- 1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.
- 2. The application has been amended as follows:

IN THE TITLE:

Delete the original title and insert:

-- THIN FILM TRANSISTOR ARRAY PANEL--

Reasons for Allowance

- 3. Claims 9-23 are allowed.
- 4. The following is an examiner's statement of reasons for allowance:

The prior art of record fails to disclose the combination of a thin film transistor array structure recited in the base claims 9 and 17. Specifically, the combination of the structure comprising: a plurality of data lines disposed on the gate dielectric layer, wherein the data lines are extended to the edge of the substrate, which are electrically connected to the second bonding pads; a first mask layer disposed over the gate dielectric layer partially covering the first bonding pads, wherein a remaining portion of

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the first bonding pads remain exposed; a second mask layer disposed over the gate dielectric layer partially covering the second bonding pads, wherein a remaining portion of the second bonding pads remain exposed; a plurality of thin film transistors disposed on the substrate, a patterned cover layer covering over the thin film transistors and the gate dielectric layers; a patterned photo resist layer disposed over the cover layer partially covering the two edges of the substrate such that the remaining portion of the two edges of the substrate are exposed (claim 9); or the combination of the structure comprising: a gate dielectric layer disposed on the substrate, wherein a portion of the first bonding pads and the second bonding pads are exposed by the gate dielectric layer, and a thickness of the gate dielectric layer located over a peripheral region of the first bonding pads and the second bonding pads is less than a thickness of the gate dielectric layer elsewhere; and a plurality of data lines disposed on the gate dielectric layer, wherein the data lines are extended to the edge of the substrate, which are electrically connected to the second bonding pads (claim 17).

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Theresa T. Doan whose telephone number is (571) 272-1704. The examiner can normally be reached on Monday to Friday from 7:00AM - 4:00PM.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, WAEL FAHMY can be reached on (571) 272-1705. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

TD February 15, 2005.

> PHAT X. CAO PRIMARY EXAMINER

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